

Search Notes

Application/Control No.

10/805,592

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

ANDERSEN ET AL.

Art Unit

2817

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 330 | 10 | 11/8/2005 | HN |
| 330 | 251 | 11/8/2005 | HN |
| 330 | 207A | 11/8/2005 | HN |
| 330 | 195 | 11/8/2005 | HN |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|-----------|----------|
| CLASSES | ABOVE | 11/8/2005 | HN |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| EAST (US-PGPUB;USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) | 11/8/2005 | HN |
| MOTTOLA STEVEN J | 11/8/2005 | HN |
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